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1	П		US	6732065 B1	20040504	23	Noise estimation for coupled RC interconnects in deep submicron	7
2	Г	Г	US	6587815 B1	20030701	16	integrated circuits Windowing scheme for analyzing noise from multiple sources	7
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5		Г	US	6397169 B1	20020528	13	interconnect network in FPGA device Adaptive cell separation and circuit changes driven by maximum capacitance	7
6	Γ	Γ	US	6353917 B1	20020305 _. 1	14	rules Determining a worst case switching factor for integrated circuit design	7
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